11N65K-MT Preliminary Power MOSFET

11A, 650V N-CHANNEL POWER MOSFET

■ DESCRIPTION

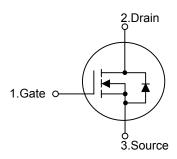
The **UTC 11N65K-MT** is an N-channel enhancement mode power MOSFET. It uses UTC advanced planar stripe, DMOS technology to provide customers perfect switching performance, minimal on-state resistance. It also can withstand high energy pulse in the avalanche and commutation mode.

The **UTC 11N65K-MT** is universally applied in electronic lamp ballasts based on half bridge topology, high efficiency switched mode power supplies, active power factor correction, etc.

■ FEATURES

- * $R_{DS(ON)}$ <1.00 Ω @ V_{GS} = 10 V, I_{D} = 5.5 A
- * Fast Switching
- * With 100% Avalanche Tested

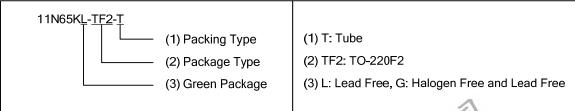
■ SYMBOL



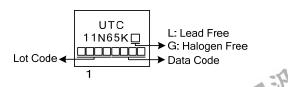
■ ORDERING INFORMATION

Ordering Number		Dookogo	Pin Assignment			Dooking	
Lead Free	Halogen Free	Package	1	2	3	Packing	
11N65KL-TF2-T	11N65KG-TF2-T	TO-220F2	G	D	S	Tube	

Note: Pin Assignment: G: Gate D: Drain S: Source



■ MARKING



1 TO-220F2

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■ **ABSOLUTE MAXIMUM RATINGS** (T_C = 25°C, unless otherwise specified)

PARAMETER		SYMBOL	RATINGS	UNIT
Drain to Source Voltage		V_{DSS}	650	V
Gate to Source Voltage		V_{GSS}	±30	V
Continuous Drain Current	T _C =25°C		11 (Note 2)	Α
Continuous Drain Current	T _C =100°C	I _D	7 (Note 2)	Α
Pulsed Drain Current (Note 3)		I _{DM}	44 (Note 2)	Α
Single Pulsed Avalanche Energy(Note 4)		E _{AS}	440	mJ
Peak Diode Recovery dv/dt (Note 5)		dv/dt	4.5	V/ns
Power Dissipation		Б	48	W
Derate above 25°C		P _D	0.38	W/°C
Junction Temperature		TJ	+150	°C
Storage Temperature		T _{STG}	-55 ~ +150	°C

Notes: 1. Absolute maximum ratings are those values beyond which the device could be permanently damaged. Absolute maximum ratings are stress ratings only and functional device operation is not implied.

- 2. Drain current limited by maximum junction temperature
- 3. Repetitive Rating: Pulse width limited by maximum junction temperature
- 4. L=7.27mH, I_{AS} =11A, V_{DD} = 50V, R_{G} =25 Ω , Starting T_{J} =25 $^{\circ}$ C
- 5. I_{SD}≤11A, di/dt≤200A/μs, V_{DD}≤BV_{DSS}, Starting T_J=25°C

■ THERMAL DATA

PARAMETER	SYMBOL	RATINGS	UNIT	
Junction to Ambient	θ_{JA}	62.5	°C/W	
Junction to Case	θ_{JC}	2.58	°C/W	



ELECTRICAL CHARACTERISTICS (T_C=25°C, unless otherwise specified)

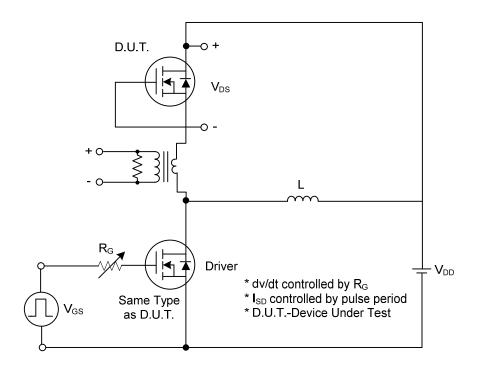
PARAMETER	SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	UNIT			
OFF CHARACTERISTICS									
Drain-Source Breakdown Voltage	BV _{DSS}	V _{GS} =0V, I _D =250μA	650			V			
Breakdown Voltage Temperature Coefficient		00 , 2		0.5		V/°C			
•	I _{DSS}	V _{DS} =650V, V _{GS} =0V			10	μA			
Drain-Source Leakage Current		V _{DS} =650V, T _J =125°C			100	μA			
Gate-Source Leakage Current	I _{GSS}	V _{DS} =0V ,V _{GS} =±30V			±100	nA			
ON CHARACTERISTICS									
Gate Threshold Voltage	$V_{GS(TH)}$	V_{DS} = V_{GS} , I_D =250 μ A	2.0		4.0	V			
Drain-Source On-State Resistance	R _{DS(ON)}	V _{GS} =10V, I _D =5.5A			1.00	Ω			
DYNAMIC PARAMETERS									
Input Capacitance	C _{ISS}			850	1200	pF			
Output Capacitance	Coss	V _{DS} =25V,V _{GS} =0V,f=1.0MHz		139	150	pF			
Reverse Transfer Capacitance	C _{RSS}			10	20	pF			
SWITCHING PARAMETERS									
Total Gate Charge	Q_{G}	V _{DS} =30V, V _{GS} =10V, I _D =0.5A		35	55	nC			
Gate-Source Charge	Q_{GS}	$V_{DS}=30V$, $V_{GS}=10V$, $I_{D}=0.5A$ (Note 1, 2)		10		nC			
Gate-Drain Charge	Q_{GD}	(14010-1, 2)		9		nC			
Turn-ON Delay Time	t _{D(ON)}			74	90	ns			
Turn-ON Rise Time	t _R	V_{DD} =50V, I_{D} =1.3A, R_{G} =3 Ω		95	120	ns			
Turn-OFF Delay Time	t _{D(OFF)}	(Note 1, 2)		180	200	ns			
Turn-OFF Fall Time	t _F			96	120	ns			
SOURCE- DRAIN DIODE RATINGS AND CHARACTERISTICS									
Maximum Body-Diode Continuous Current	I _S				11	Α			
Maximum Body-Diode Pulsed Current	I _{SM}				44	Α			
Drain-Source Diode Forward Voltage	V_{SD}	I _S =11A, V _{GS} =0V			1.4	V			
Body Diode Reverse Recovery Time	t _{rr}	V _{GS} =0V, I _S =11A,		90		ns			
Body Diode Reverse Recovery Charge	Q_{RR}	dI _F /dt=100A/μs (Note 1)		1.5		μC			

Notes: 1. Pulse Test: Pulse width ≤ 300µs, Duty cycle ≤ 2%

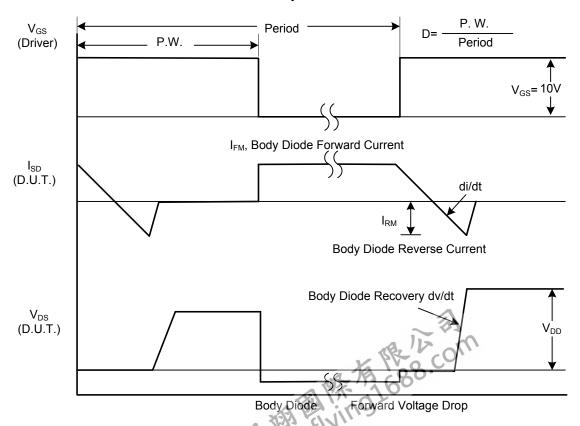


^{2.} Essentially independent of operating temperature

■ TEST CIRCUITS AND WAVEFORMS

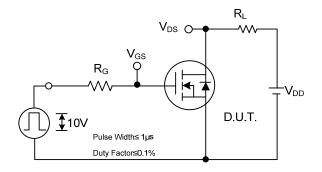


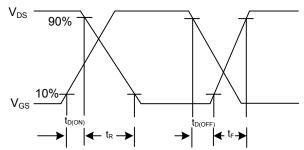
Peak Diode Recovery dv/dt Test Circuit



Peak Diode Recovery dv/dt Waveforms

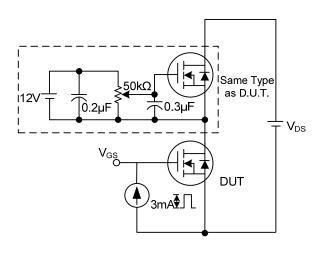
TEST CIRCUITS AND WAVEFORMS (Cont.)

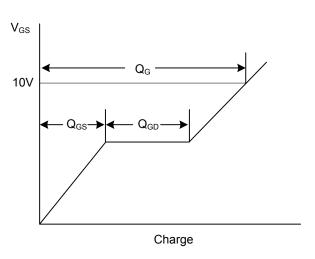




Switching Test Circuit

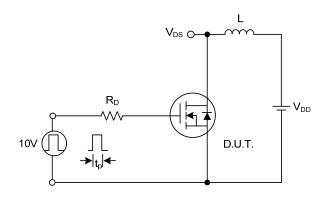
Switching Waveforms

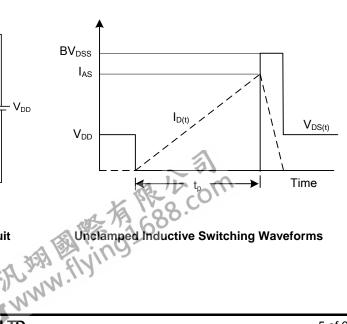




Gate Charge Test Circuit

Gate Charge Waveform





Unclamped Inductive Switching Test Circuit

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